



ALPHA & OMEGA
SEMICONDUCTOR



AOU452

N-Channel Enhancement Mode Field Effect Transistor

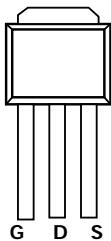
General Description

The AOU452 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications. Standard Product AOU452 is Pb-free (meets ROHS & Sony 259 specifications). AOU452L is a Green Product ordering option. AOU452 and AOU452L are electrically identical.

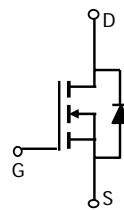
Features

$V_{DS} (V) = 25V$
 $I_D = 55 A (V_{GS} = 10V)$
 $R_{DS(ON)} < 9 m\Omega (V_{GS} = 10V)$
 $R_{DS(ON)} < 15 m\Omega (V_{GS} = 4.5V)$

TO-251



Top View
Drain Connected
to Tab



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	25	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^G	I_D	55	A
$T_C=100^\circ C$		40	
Pulsed Drain Current ^C	I_{DM}	100	
Avalanche Current ^C	I_{AR}	30	A
Repetitive avalanche energy $L=0.1mH$ ^C	E_{AR}	135	mJ
Power Dissipation ^B	P_D	50	W
$T_C=100^\circ C$		25	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	Steady-State	$R_{\theta JA}$	39	°C/W
Maximum Junction-to-Case ^B	Steady-State	$R_{\theta JC}$	2.5	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	25			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$	$T_J=55^\circ\text{C}$	1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.8	3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	100			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$		7	9	$\text{m}\Omega$
			$T_J=125^\circ\text{C}$		10	
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$			12	15
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=10\text{A}$		35		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.72	1	V
I_s	Maximum Body-Diode Continuous Current				55	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=12.5\text{V}, f=1\text{MHz}$		1230	1476	pF
C_{oss}	Output Capacitance			315		pF
C_{rss}	Reverse Transfer Capacitance			190		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.2	1.45	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=12.5\text{V}, I_D=20\text{A}$		26.4	32	nC
$Q_g(4.5\text{V})$	Total Gate Charge			13.5		nC
Q_{gs}	Gate Source Charge			3.9		nC
Q_{gd}	Gate Drain Charge			7.75		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=12.5\text{V}, R_L=0.6\Omega, R_{\text{GEN}}=3\Omega$		6.5		ns
t_r	Turn-On Rise Time			10		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			22.7		ns
t_f	Turn-Off Fall Time			6.2		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		23.06	27.5	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		15.25		nC

A: The value of R_{IA} is measured with the device in a still air environment with $T_A=25^\circ\text{C}$.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$.

D. The R_{IA} is the sum of the thermal impedance from junction to case R_{JC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\ \mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$.

G. The maximum current rating is limited by bond-wires.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

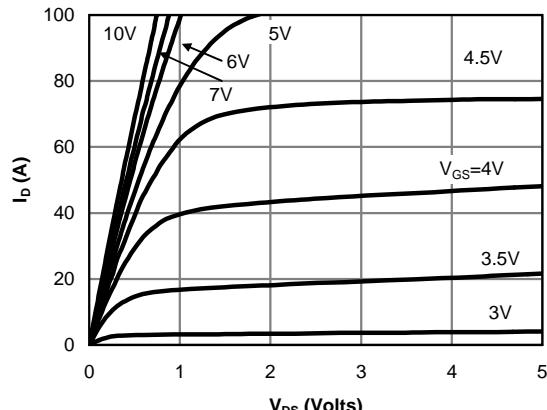


Fig 1: On-Region Characteristics

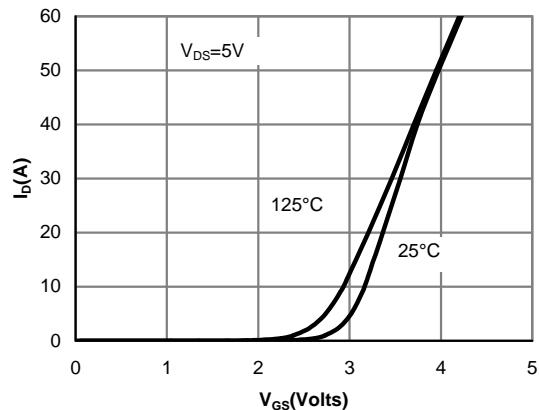


Figure 2: Transfer Characteristics

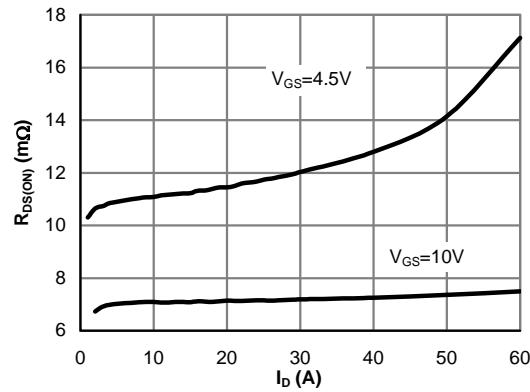


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

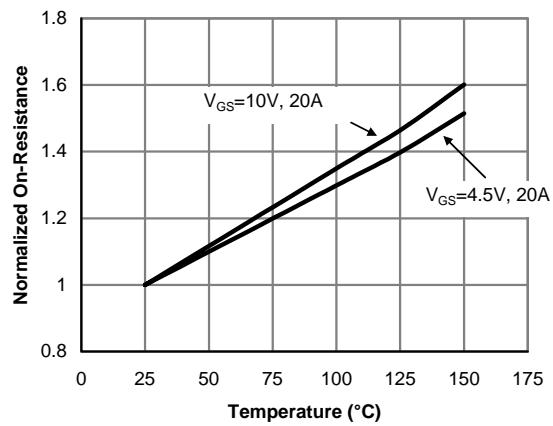


Figure 4: On-Resistance vs. Junction Temperature

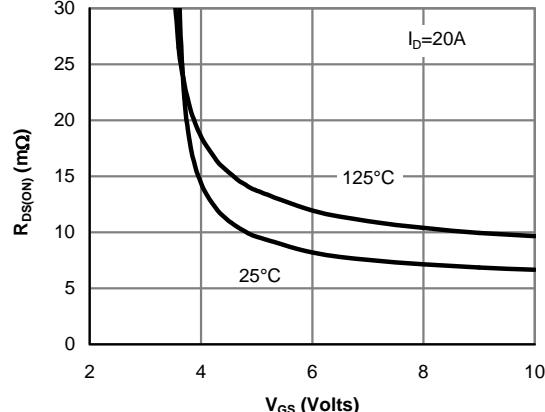


Figure 5: On-Resistance vs. Gate-Source Voltage

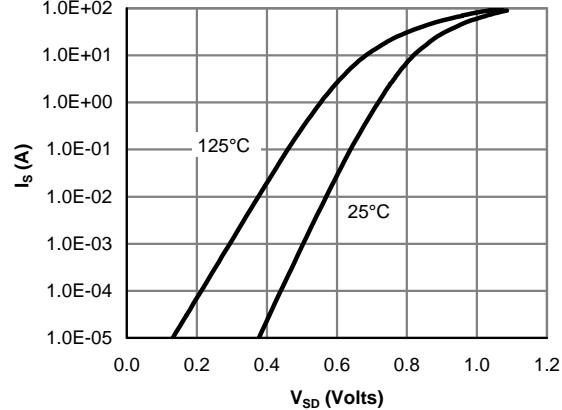


Figure 6: Body-Diode Characteristics

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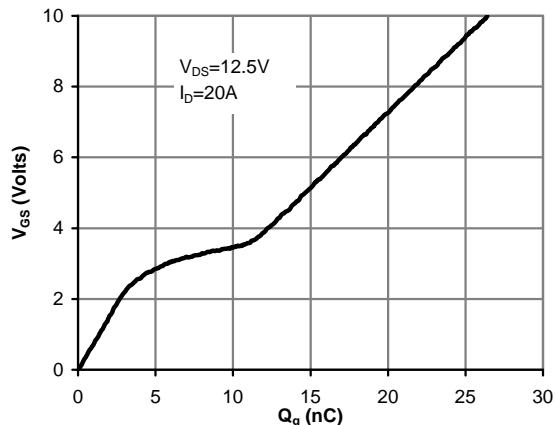


Figure 7: Gate-Charge Characteristics

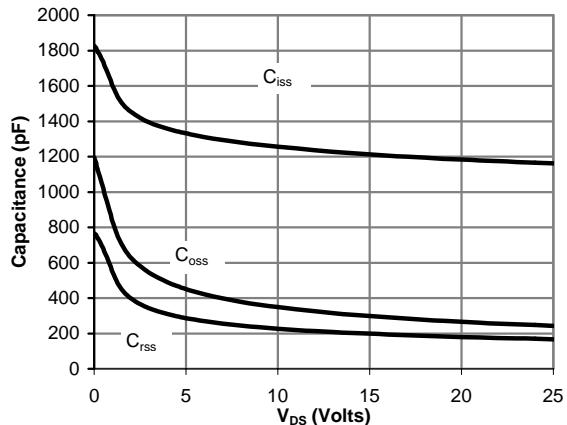


Figure 8: Capacitance Characteristics

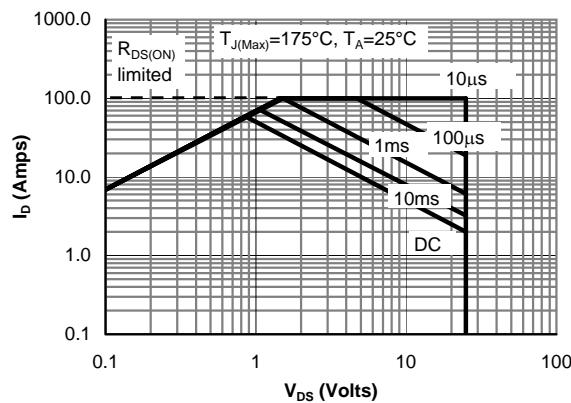


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

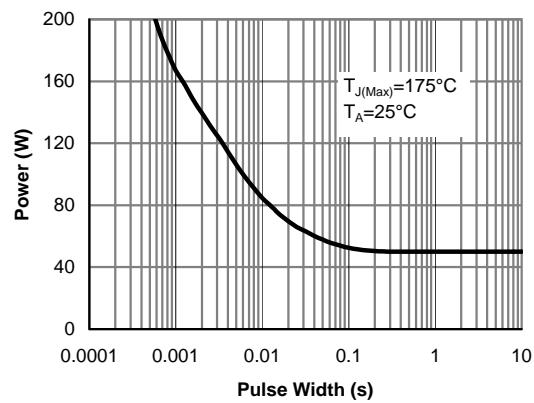


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

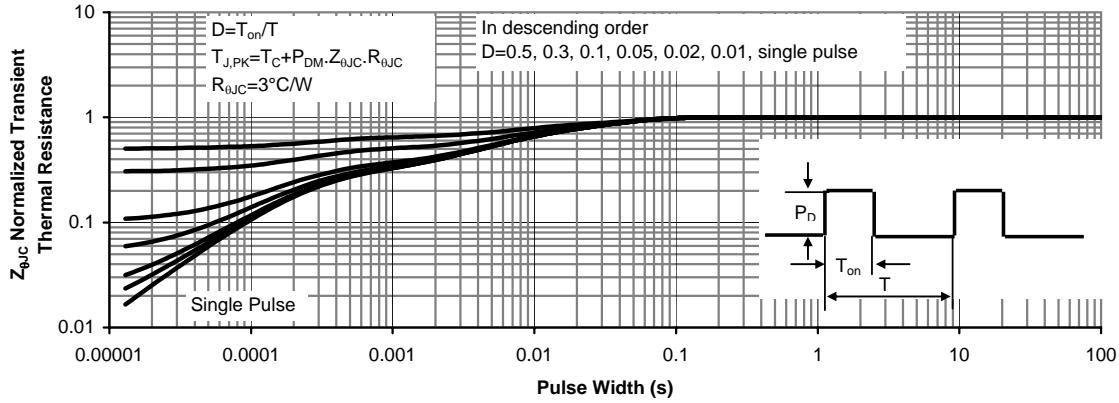


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

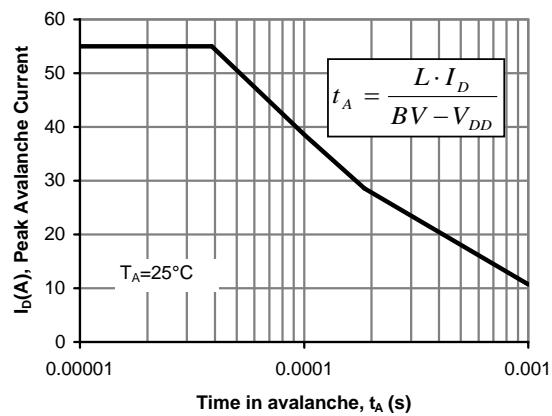
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Single Pulse Avalanche capability

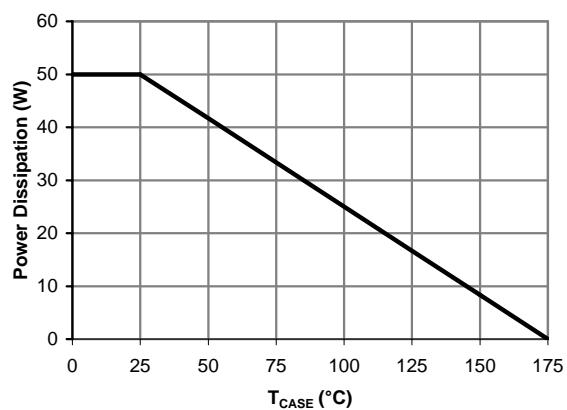


Figure 13: Power De-rating (Note B)

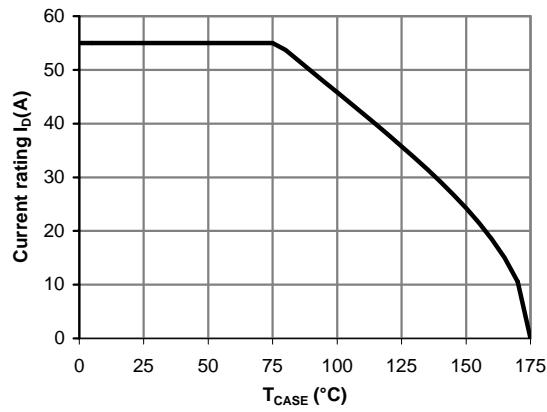


Figure 14: Current De-rating (Note B)